

World Leader in

Micro & Nano Analysis

ATOM PROBE TOMOGRAPHY Seminar Oct. 4th

Center for Advanced **Energy Studies**

A Review of CAMECA's product line (SIMS/EPMA/APT) and a detailed overview of Atom Probe Tomography Technology, its Applications, and The Latest Technology



LEAP 6000 XR

This presentation will introduce CAMECA SIMS/EPMA and APT products and will then review the cutting-edge APT technology, applications, and typical 3D nanoscale data analysis techniques.

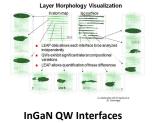
An overview of APT applications, especially Material Science, Metals and Alloys, Geologic, Nuclear, Batteries, Fuels Cells and more will be provided. The talk will highlight technology advances that have enabled analysis of material systems and structures far beyond the early limitations of APT to simple grain boundary analysis of bulk metals. The maturation atom probe hardware and software along with the advancements in FIB-based specimen preparation methods have made site-specific analyses truly routine.

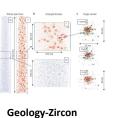
We will then invite discussion/Q&A on the use of CAMECA microscopes for specific applications of interest to the attendees. - Bring your Questions and research proposals!

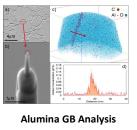
Wednesday 10/4 3 pm – CAES Auditorium



Nanoscale Clustering









About the Speaker: Robert Ulfig has been working with Atom Probe Microscopes at CAMECA in Madison since 2001. He currently works as a Sr. Product Manager, integrating the activities and requests from internal and external customers into the latest and greatest of CAMECA's software and hardware. Rob graduated from The University of Wisconsin-Madison with Materials Science and, Nuclear Engineering, and Engineering Physics degrees.

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